Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L3	45063	(level or height)near(light)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/03/01 07:35
L4	1229	356/500,498,496,450.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/01 07:35
.L5	33	3 and L4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/03/01 07:40
L7	2033	light same projec\$4 same (below or underneath) same stage	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON .	2007/03/01 07:43
L8	7	4 and 7	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/03/01 07:47
L9	1134	(underneath or below ) same interferometer same light	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/03/01 07:48
L10	77	4 and 9	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/03/01 07:48
L14	16	z adj axis adj interferometer	USPAT	OR	ON	2007/03/01 08:18
L24	10	((RIKI) near2 (OGAWA)).INV.	US-PGPUB; USPAT	OR	ON	2007/03/01 12:53

L25	22	((MITSUO) near2 (TABATA)).INV.	US-PGPUB; USPAT; USOCR	OR	ON	2007/03/01 12:56
S1	2786	382/141,144,145,147.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/01 07:32
S2	97973	(height or level) adj adjust\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/02/21 08:59
<b>S3</b>	32	S1 and S2	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/02/21 09:00
S5	55550	(height or focus or level) adj adjustment	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/21 09:39
S6	45	S1 and S5	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/21 09:39
S18	9	adjust\$4 same surface same level same (intensit\$3 adj threshold)	US-PGPUB; USPAT; USOCR	OR	ON	2007/02/21 11:13
S21	10	adjust\$4 same surface same (level or height) same (intensit\$3 adj threshold)	US-PGPUB; USPAT; USOCR	OR	ON	2007/02/21 11:15
S24	151	adjust\$4 same (level or height) same (intensit\$3 adj (threshold or difference))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/21 11:20

S25	213840	piezoelectric	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/21 11:19
S26	4	S24 and S25	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/21 11:16
S27	58810	piezoelectric adj element	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/21 11:19
S34	264	S32 and S33	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/21 11:24
S35	6	S27 and S34	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/21 11:24
S38	2786	382/141,144,145,147.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/02/21 12:12

S47	21	(US-20020001403-\$ or US-20030170552-\$).did. or (US-5454049-\$ or US-6775006-\$ or US-4639139-\$ or US-4732483-\$ or US-4657393-\$ or US-5133601-\$ or US-7120286-\$ or US-6937754-\$ or US-5784164-\$ or US-4818110-\$ or US-6956963-\$ or US-5355223-\$ or US-5398113-\$ or US-5173746-\$ or US-4576479-\$ or US-5555090-\$ or US-4577095-\$ or US-5402234-\$ or US-4333007-\$).did.	US-PGPUB; USPAT	OR	ON	2007/02/21 13:50
S48	73878	height and threshold	US-PGPUB; USPAT	OR	ON	2007/02/21 13:50
S49	5	S47 and S48	US-PGPUB; USPAT	OR	ON	2007/02/21 14:02
S59	1585623	((platform or stage ) adj height) same adjustment or detection	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/21 14:22
S60	2786	382/141,144,145,147.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/02/21 14:22
S61	1357	S60 and S59	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/21 14:22
S62	3146	piezoelectric and photoelectric	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/21 14:22
S63	6	S61 and S62	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR .	ON	2007/02/21 14:23

S83	2788	382/141,144,145,147.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/02/22 11:24
S10 2	594	readjust\$3 same (height or level) same (stage or surface or platform) same (focus or reference)	US-PGPUB; USPAT; USOCR	OR	ON	2007/02/22 08:59
S10 6	2	S83 and S102	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR .	ON	2007/02/22 08:59
S11 7	1	(specimen adj surface) adj (target or reference) adj (level or height)	US-PGPUB; USPAT; USOCR	OR	ON	2007/02/22 11:12
S13 9	28166	photodetector and voltage	US-PGPUB; USPAT; DERWENT	OR	ON	2007/02/22 12:28
S14 3	97591	photoelectric	US-PGPUB; USPAT; DERWENT	OR	ON	2007/02/22 12:36
S14 4	16	S138 and S143	US-PGPUB; USPAT; DERWENT	OR	ON	2007/02/22 12:54
S14 5	21	z-height near adjustment	US-PGPUB; USPAT; DERWENT	OR	ON	2007/02/22 12:58
S17 9	196395	(control\$4 or adjust\$4) same (height or level) same (specimen or sample or stage)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/26 10:15
S18 0	137	(reflected adj light ) same (less adj2 threshold)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/26 10:19

						<del></del>
S18 1		S179 and S180	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/26 10:16
S26 0	952	stage adj heights	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/02/26 16:05
S26 1	2788	382/141,144,145,147.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/02/26 16:04
S26 2		S261 and S260	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/02/26 16:04
S26 3	21	wafer adj stage adj heights	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/02/26 16:07
S26 4	1	wafer adj stage adj heights adj (measurement or calculat\$3 or detect\$4)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/02/26 16:09
S27 9	1228	356/500,498,496,450.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/02/27 15:19
S28 0	9946	(first and second) near (light adj source)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/02/27 15:26

S28 1	18	S279 and S280	US-PGPUB; USPAT; USOCR; EPO; JPO;	AND	ON	2007/02/27 15:20
			DERWENT; IBM_TDB			·